AN8230K

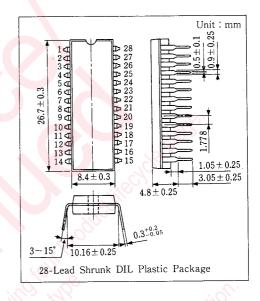
IC for FDD Motor Drive Control

■ Outline

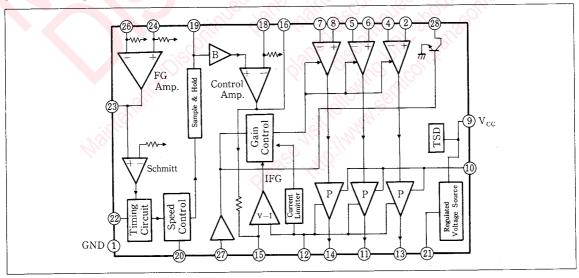
The AN8230K is an FDD motor drive control IC in which a frequency-controlled speed control circuit and a 3-phase full wave drive circuit are integrated on a single chip.

■ Features

- Total current in stop mode: less than 0.3mA
- Current-limit circuit
- Thermal shut-down circuit
- Maximum output current: 500mA



Block Diagram





Pin

Pin No.	Pin Name		Pin Name		
1	GND	15	Vi Conv. Ripple Reduction		
2	Hall Amp.Input(Ha ⁺)	16	Cont. Amp. Output		
3	NC	17	NC		
4	Hall Amp.Input(Ha ⁺)	18	Cont. Amp. Input		
5	Hall Amp.Input(Ha ⁻)	19	Sample & Hold		
6	Hall Amp.Input(Hb ⁺)	20	Speed Control		
7	Hall Amp.Input(Hc ⁻)	21	Vs		
8	Hall Amp.Input(Hc ⁺)	22	Ref. O _{sc} .		
9	V _{cc}	23	FG Amp. Output		
10	V_{M}	24	FG Amp. Input(+)		
11	Current Output	25	NC		
12	GND(Power)	26	FG Amp. Input(-)		
13	Current Output	27	Start/Stop		
14	Current Output	28	Hall Element Bias		

■ Absolute Maximum Ratings (Ta=25°C)

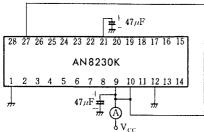
Item	Symbol	Rating	Unit
Supply Voltage	V _{cc}	18	V
Power Dissipation	P _D	1780	mW
Output Current	Io	±500	mA
Hall Input Voltage Range	V _{HB}	2.2~8.5	V
Operating Ambient Temperature	Topr	$-20 \sim +70$	c
Storage Temperature	Tstg	$-55 \sim +150$	°C

■ Electrical Characteristics (Ta=25°C)

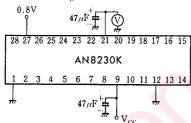
Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Standby Supply Current	I_{cs}	İ	$V_{\text{STOP}} = 12, V_{\text{M}} = 12V$		2	0.3	mA
No-load Supply Current	I _{CM}	2	$V_{\rm M} = 12 {\rm V}, \ V_{\rm VI} = 1.7 {\rm V}$	10.	"	15	mA
Stabilized Supply Voltage	Vs	3	$V_{\text{STOP}} = 0.8V$	4.0	4.5	5.2	V
Start/Stop Input Voltage "H"	$V_{\mathtt{STH}}$	4	$V_{cc}=9.6V$	2			V
Start/Stop Input Voltage "L"	$V_{\mathtt{STL}}$	5	$V_{cc}=9.6V$			0.8	V
Start/Stop Input Current "H"	I _{sth}	4	$V_{STOP} = 2V$		<u> </u>	100	nA
Start/Stop Input Current "L"	I _{STL}	5	$V_{STOP} = 0.8V$	-150			μΑ
Hall Bias Current (for pins)	Інв	6	$V_{VI} = 3.2V, V_{HIL} = 2.5V, V_{HIH} = 3.2V$			3	μΑ
FG Amp. Input Bias Voltage"+"	$V_{\rm FG}^{+}$	7	$V_{vi} = 1.7 V, V_{STOP} = 0.8 V$	2.0	2.25	2.6	V
FG Amp. Input Bias Voltage"-"	V_{FG}^-	7	$V_{VI} = 1.7V, V_{STOP} = 0.8V$	2.0	2.25	2.6	V
Schmitt Amp. Input Bias Voltage "H"	V _{sh}	8	$V_{STOP} = 0.8V, I_{FG}^{+} = 50 \mu A$			4	V
Schmitt Amp. Input Bias Voltage "L"	V _{sL}	. 8	$V_{STOP} = 0.8V, I_{FG} = -50\mu A$	1			V
Speed Control Input Bias Current	$I_{\scriptscriptstyle \mathrm{SP}}$	9	$V_{SP} = 2.3V$, $V_{CC} = 16V$, $V_{OSC} = 0V$, $V_{STOP} = 0.8V$			100	nA
S/H Input Bias Current	I _{SHB}	10	$V_{SH} = 2.3V$, $V_{CC} = 16V$, $V_{OSC} = 0V$, $V_{STOP} = 0.8V$			100	nA
Output Voltage "L"	Vol	11	$I_{oL} = 300 \text{mA}, V_{vI} = 3.2 \text{V}, V_{cC} = V_{M} = 9 \text{V}$			1	V
Current Limit Reference Voltage	V _{LM}	12	$V_{M} = 12V, V_{VI} = 3.2V$		0.5	0.55	V

 $[\]begin{array}{lll} Note \ 1) & V_{cc}\!=\!12V, \ V_{\text{STOP}}\!=\!0V, \ V_{\text{PG}}\!=\!0V \ \text{in case of no specific conditions} \\ Note \ 2) & Supply \ power \ to \ V_{cc} \ and \ V_{\tiny M} \ simultaneously, \ or \ V_{\tiny M} \ first. \end{array}$

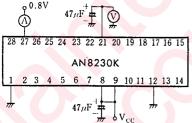
Test Circuit 1 (I_{CS})



Test Circuit 3 (Vs)

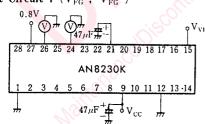


Test Circuit 5 (V_{STL}, I_{STL})

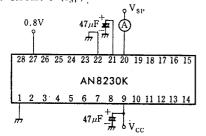


- When 0.8V is applied to Pin ②, measure Pin ② voltage to check that the stabilized power circuit is turned ON.
- Measure the current value when 0.8V is applied to Pin ②

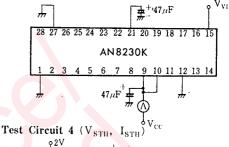
Test Circuit 7 (V_{FG}⁺, V_{FG}⁻)



Test Circuit 9 (ISP)



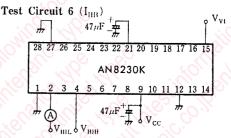
Test Circuit 2 (I_{CM})



47,4F # W # # W # # W # # W # # W # # W # # W # # W # # W # # W # # W # # W #

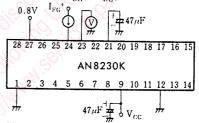
 When 2V is applied to Pin @, measure Pin @ voltage to check that the stabilized power circuit is turned ON.

• Measure the current value when 2V is applied to Pin 2.



• Apply V_{HIL} to the measuring pin to measure I_{HB} . Similar procedure is made for Pins 4 to 8.

Test Circuit 8 (VSH, VSL)



Test Circuit 10 (I_{SHB})

47μF

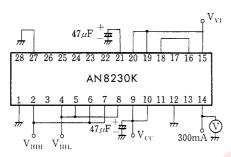
0.8V

28 27 26 25 24 23 22 21 20 19 18 17 16 15

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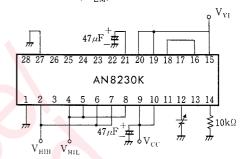
1 2 3 4 5 6 7 8 9 10 11 12 13 14

Test Circuit 11 (V_{OL})



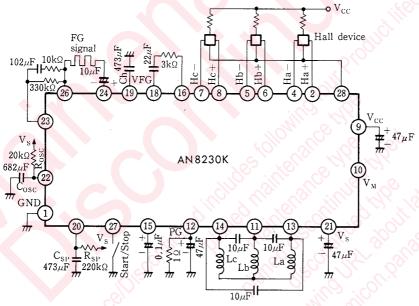
• Measure Pin @ voltage when 300mA is applied to it.

Test Circuit 12 (V_{LM})



ullet Change the voltage to be applied to Pin $\hbox{$\mathbb Q$}$ and measure the voltage when Pin $\hbox{$\mathbb Q$}$ becomes from "H" to "L" .

■ Application Circuit



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